

NEOSEM

Supported Protocols

- PCIe 2.0, PCIe 3.0
- SATA 3/6 Gbps (F-4A)
- SAS 3/6/12 Gbps(F-4A)
- AHCI, NVMe

Supported Form Factors

- Edge Card (AIC)
FHHL, HHHL
- 1.8", 2.5"
- U.2
- mSATA (F-4A)
- M.2

System Scalability

- **F-8A (Ambient)**
Bench-top Tester
Up to 4 Parallel DUTs
- **F-60B (+10C to +85C)**
1-zone Chamber
Up to 120 Parallel DUTs(AIC)
Up to 240 Parallel DUTs (M.2)
- **F-60E (-34C to +85C)**
1-zone Chamber
Up to 192 Parallel DUTs(AIC)
Up to 384 Parallel DUTs(M.2)

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F-8A Benchtop PCIe SSD Test System



F-8A Ambient PCIe SSD Benchtop Test System

The Neosem's F-8A ambient, SSD or HDD test system has a small footprint and is affordably priced making it easy to provide every engineer with their own testing platform. This system utilizes Neosem's robust Andromeda operating software platform with a comprehensive library of standard tests.

Key Features

- Small Benchtop footprint and Build in PC
- Tailored to SSD Testing with AHCI, NVMe interfaces
- Programmable power margining per DUT with current and voltage measurement read-back
- Turnkey solution, featuring Neosem's Andromeda operating software
- User-friendly GUI allows for easy test control (start/stop) and monitoring (status) of all Device Under Test (DUT) on one screen
- Provides characterization data such as performance, measurement, throughput, IOPs, thermal and power consumption
- GUI allows intuitive drill down monitoring from scripts level through DUT interface commands and down to bit level write and operations
- Comprehensive library of engineering, reliability, quality and production test scripts designed for NVME SSD devices

F-8A SSD Test System

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Product Specifications

Mechanical

- Exterior Dimensions: 8" wide x 11" tall x 30" deep

Input Power

- 120 VAC @5A / 220VAC @ 3A

Software

- Test results are delivered in clear, Detailed reports and graphs
- Test script development tools
- GUI driven test control platform
- Debug through interactive shell command interface
- Individually captured information for every DUT
- Run multiple tests, simultaneously
- API for user-defined plug-ins
- Java Support
- SNIA and JEDEC Compliance Test



Applications

- Device Verification Testing (DVT)
- Engineering Verification Testing (EVT)
- Device Screening
- Return Material Authorization (RMA)



Supported Protocols

- HDD 2.5" , 3.5"
- PCIe 2.0, PCIe 3.0
- SATA 3/6 Gbps (F-4A)
- SAS 3/6/12 Gbps (F-4A)
- AHCI, NVMe

Supported Form Factors

- Edge Card (AIC)
FHHL, HHHL
- 1.8", 2.5", 3.5"(F-4A)
- U.2
- mSATA (F-4A)
- M.2

System Scalability

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F-8A Tester System Specifications

HDD (2.5") F-4A only	1 DUT
HDD (3.5") F-4A only	1 DUT
PCIe SSD (F-8A only)	4 DUTs (AIC) 8 DUTs (M.2)
All in One PC	Stand Alone SSD Tester
Test Application Development	P25 Script & JAVA Support
Tester Input Power	120-240V AC – 50 to 60HZ
Tester Operating Temperature Range	18 to 28C – Air cooled
Tester Software	Andromeda Operating S/W

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